

## PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Serial No.: 10/701,332 )  
Filed: November 4, 2003 ) Conf. No.: 5874  
Title: A Novel BISR Mode to Test )  
the Redundant Elements and )  
Regular Functional Memory )  
to Avoid Test Escapes )  
Inventor: Ghasi R. Agrawal et al. )  
Art Unit: 2117 )  
Examiner: Steve N. Nguyen )  
Atty. Ref: 03-1343 )

**RESPONSE TO THE OFFICE ACTION MAILED NOVEMBER 21, 2008**

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In the matter of the above-identified application and in response to the Office Action mailed November 21, 2008, kindly enter the following amendments and consider the following remarks toward reconsideration of the present application.